

Inelastic X-ray scattering from Phonons at the ESRF



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Outline

Introduction

Highlights from "standard" experiments

Recent developments

- Phonon density-of-states
- Phonons at surfaces
- Polycrystalline materials -> single crystal properties
- IXS and (thermal) diffuse scattering

Outlook



Inelastic Scattering from Phonons





The instrument INELAX at the HARWI wiggler line of HASYLAB.

Burkel, Dorner and Peisl (1987)

Hard X-rays: $E_i = 18 \text{ keV}$ $k_i = 91.2 \text{ nm}^{-1}$ $\Delta E/E \le 1 \times 10^{-7}$ small beam

Brockhouse (1955)

Thermal neutrons: $E_i = 25 \text{ meV}$ $k_i = 38.5 \text{ nm}^{-1}$ $\Delta E/E = 0.01 - 0.1$ large beam



Scientific themes (I)

Disordered systems: Explore new Q-E range



- Interplay between structure and dynamics
- Structural and other relaxations
- Excess of the VDOS (Boson peak)
- Nature of sound propagation and attenuation



Scientific themes (II)

Crystalline systems: small samples, high pressure



V = 10⁻⁴ – 10⁻⁵ mm³

Diamond anvil cells

Thin films and surfaces



- correlated electron systems
 - actinides, superconductors, CDW systems
- novel materials
- "old" materials at very high pressures
- minerals relevant in Earth science



Phonon dispersion of PuCoGa₅



- Sample : ²⁴²Pu from Ga flux method (ITU Karlsruhe)
- Ab-initio calculation : GGA + U; (P. Piekarz et al., Phys. Rev. B 72, 01452 (2005))

The European Light Source

S. Raymond et al.; Phys. Rev. Lett. 96, 237003 (2006)





- Main effect : softening of some phonon frequencies in relation with U > 0

=> Sensitivity of phonon spectrum to 5f charge distribution

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OH-stretching vibrations in diaspore





AlOOH, orthorhombic H-bond of intermediate strength



The European Light Source

B. Winkler, A. Friedrich et al.; in preparation (2007)

European Synchrotron Radiation Facility





	E _{exp} [meV]	E _{theo} [meV]
(2.5 0 -1)	374	375
(2.5 0 0)	357	357

B. Winkler, A. Friedrich et al.; in preparation (2007)

350

300

400

X Axis Title

450



IXS at very high pressures



Gasket Ruby

Sample

Pressure measurement by frequency shift of ruby fluorescence

